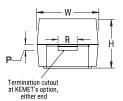


T543D106K050AHW100

T543 HRA, Tantalum, Polymer Tantalum, HRA, 10 uF, 10%, 50 VDC, SMD, Polymer, Molded, Up Screening, N/A, 100 mOhms, 7343, 3.1 mm, 1.3 mm

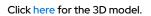
CATHODE (-) END VIEW



ANODE (+) END VIEW

shape/design at KEMET's option

SIDE VIEW



General Information	
Series	T543 HRA
Dielectric	Polymer Tantalum
Style	SMD Chip
Description	SMD, Polymer, Molded, Up Screening
Features	Non-Combustible, Low ESR, High Reliability
RoHS	No
Prop 65	WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov /
SCIP Number	b064b03e-bd75-42af-b342-1fe 94dec2340
Termination	Tin Lead (SnPb)
AEC-Q200	No
Typical Component Weight	352.36 mg
Shelf Life	52 Weeks
MSL	3

Dimensions	
L	7.3mm +/-0.3mm
W	4.3mm +/-0.3mm
н	2.8mm +/-0.3mm
т	0.13mm REF
S	1.3mm +/-0.3mm
F	2.4mm +/-0.1mm
A	3.8mm MIN
В	0.5mm +/-0.15mm
E	3.5mm REF
G	3.5mm REF
Р	0.9mm REF
R	1mm REF
х	0.1mm +/-0.1mm REF

Typical Component Weight	352.36 mg
Shelf Life	52 Weeks
MSL	3
Specifications	
Capacitance	10 uF
Tolerance	10%
Voltage DC	50 VDC (105C), 33.5 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	105°C
Humidity	60C, 90% RH, 500 Hours
Dissipation Factor	10% 120Hz 25C
Failure Rate	N/A
ESR	100 mOhms (100kHz)
Ripple Current	1500 mA (rms, 100kHz 45C)

50 uA (5min 25°C)

10 Cycles Surge Current Testing At -55C And +85C

Packaging SpecificationsPackagingT&R, 178mmPackaging Quantity500

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute – and we specifically disclaim – any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

Leakage Current

Testing and Reliability